

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/672,357	FU ET AL.
	Examiner	Art Unit
	Binh X. Tran	1765

SEARCHED

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438	708	4/19/2006	BT
438	709	4/19/2006	BT
438	717	4/19/2006	BT
438/725		4/19/2006	BT